

Curriculum Vitae



Name: Eng. Anis Musa Nazer

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Personal Data :

Education:

- M.Sc. in Computer Engineering, American University of Beirut, Lebanon, 2006
- B.Sc. in Computer Engineering, American University of Beirut, Lebanon, 2003

Experience:

2006 – Present: Lecturer , Philadelphia University/Jordan.

2003 – 2006: Graduate assistant, American University of Beirut

Publications :

Journal publications

- (1) Anis Nazer, Ali Chehab, Ayman Kayssi “Dynamic Current Testing For CMOS Domino Circuits ”, International Journal of Electronics, 2007

Conference papers

- (1) Anis Nazer, Ali Chehab, Ayman Kayssi “Dynamic Current testing for CMOS Domino Circuits”, Midwest Symposium on Circuits and Systems, 2006
- (2) Anis Nazer, Ali Chehab, and Ayman Kayssi, and Rafic Makki. ”Evaluation of IDDT testing for CMOS domino circuits”,IEEE International Workshop on Current and Defect Based Testing, DBT 2005.
- (3) Najwa Aaraj, Anis Nazer, Ali Chehab, and Ayman Kayssi. “Transient Current Testing for Dynamic CMOS Circuits”, IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems, 2004.
- (4) Ali Chehab, Ayman Kayssi, Anis Nazer, Najwa Aaraj “Transient Current Testing of Dynamic CMOS Circuits in the Presence of Leakage and Process Variation” Intrnational Conference on Microelectronics, 2004
- (5) Ali Chahab, Ayman Kayssi, Anis Nazer and Rafic Makki, "Improved Method for iDDT Testing in the Presence of Leakage and Process Variation”, IEEE International Workshop on Current and Defect Based Testing 2004.

Consultation, and Training Activities:

Technical training in Computer Networks and Software Development at Dar Al-Handasah, Shair and Partners.

Professionals Affiliations:

1. A member of Institute of Electrical & Electronic Eng. "IEEE"
2. A member of IEEE computer society.
3. A member of Jordan Engineers Association.